

RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS2165	Apr-96	9534 B1	ANAM, PI	DK523559AAC	2.0μ OXIDE	24 PDIP

STRESS/JOB NO.

**READPOINT
(Sample Size/No. of Fails)**

Preconditioning:
T/C: -55°C to +125°C, 10~
I/L: 125°C, 7.0 V., 48 Hrs
P-17245

<u>Electrical</u>	<u>Cum %</u>
230/2	0.9%
2-F1	

Sonoscan
P-17244

<u>Zero Hour</u>
2/0

Infant / High Voltage Life
125°C, 7.0 V.
P-17245, P-17318

<u>48 Hr</u>	<u>336 Hr</u>	<u>1KHr</u>	<u>*Failure Rate</u>
230/2	77/0	77/0	102 Fits
2-F1			

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle
-55°C to +125°C
P-17319

<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>
36/0	36/0	0.0%

Biased Moisture
85°C/85% RH, 5.5 V.
P-17320

<u>274 Hr</u>	<u>959 Hr</u>	<u>Cum %</u>
77/0	77/0	0.0%

Autoclave
121°C/100% RH, 2 Atmos
P-17321

<u>96 Hr</u>	<u>Cum %</u>
38/0	0.0%

Failure Mode

F1: 2-Functional

Failure Analysis

In process